

TITLE OF THE INVENTION

SDH TEST APPARATUS AND SDH TEST METHOD

CROSS-REFERENCE TO RELATED APPLICATIONS

5 This application is based upon and claims the benefit of priority from the prior Japanese Patent Application No. 2000-009739, filed January 19, 2000, the entire contents of which are incorporated herein by reference.

BACKGROUND OF THE INVENTION

10 The present invention relates to a SDH test apparatus and a SDH test method, and particularly a SDH test apparatus for substituting a part of payload of received SDH data with a desired data and transmitting, wherein the time difference between processing for SOH
15 portion and processing for AU portion can be absorbed by a simple configuration and a SDH test method.

Conventionally, in the STM (synchronized transfer mode) system for multiplexing a plurality of series of data in synchronization and transferring, SDH
20 (synchronized digital hierarchy) data is used.

As it is well known, there are various standard for STM, and as for SDH data prescribed by the most basic STM-1, one frame is composed of a SOH (section overhead) portion of 9×9 bytes and a payload of
25 261×9 bytes, as shown in FIG. 5A.

As shown in FIG. 5B, as for SDH data, SOH portion and payload are transferred alternatively by 9 bytes

and 261 bytes respectively.

Here, information is inserted into the payload of SDH data taking a position A (this position is a position later in time than the AU pointer AUP insertion position) indicated by the value of AU (administrative unit) pointer AUP inserted at the fourth byte of SOH portion as leading head position.

Before testing the operation of systems or the like for data communication using this SDH data, sometimes it is desired to test by substituting a part of payload of SDH data to be transferred with a desired data (for instance, pseudo random signal).

In order to insert a desired data into a part of payload of SDH data and output in this way, it is necessary to proceed as follows.

First, SOH portion and payload are extracted from the input SDH data, and a desired data is inserted into a desired position of the payload for generating data for transmission.

Next, SDH data frame is generated based on this generated data and SOH data extracted from the reception data and output.

However, when a new data is generated by rewriting a part of payload, as it takes longer time than the processing time of SOH data, it is inconvenient to generate a frame data by simply combining SOH portion of received SDH data and data of newly generated

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payload section.

In other words, that is, if, frame data is generated by a simple combination as mentioned above, information lead head position is shifted by the
5 difference of payload processing time and SOH data processing time.

In order to solve this problem, in the prior art, the processing of SOH data is delayed according to data processing time of the payload.

FIG. 7 shows a configuration of a SDH test
10 apparatus 10 of the prior art for generating SDH data by delaying the processing for SOH data.

This SGH test apparatus 10 comprises a reception
SOH processing portion (Rx SOH processor) 11 for
15 performing various processing including frame detection of received SDH data, channel selection, detection of data inserted into the SOH portion, error check or others, a reception AU processing portion (Rx AU
processor) 12, a transmission AU processing portion (Tx
20 AU processor) 13 for generating AU data by substituting data of a predetermined position of the payload of data extracted by the Rx AU processor 12 with a desired data, a delay processing portion 14 for delaying
SOH data processed by the Rx SOH processor 11 by the
25 data processing time by the Tx AU processor 13 and outputting, and a transmission SOH processing portion (Tx SOH processor) 15 for generating and outputting

SDH frame data, base on AU data generated by the Tx AU processor 13 and SOH data from the delay processing portion 14.

Thus, SDH data of which data at a desired position of AU portion is substituted with a desired data can be output, for input SDH data, by delaying SOH data detected by the Rx SOH processor 11 by the processing time of AU data by the Rx AU processor 12 and the Tx AU processor 13.

However, as mentioned above, in the method of delaying the processing for SOH data, the circuit scale of the delay processing portion 14 increases extremely and inconveniently.

Especially, for the multi-channeled SDH data, the number of delay phase increases and its circuit scale increases extremely as much.

In other words, SOH data of the number of channels is output at a high speed from the Rx SOH processor 11 to the delay processing portion 14.

On the other hand, the Rx AU processor 12 processes AU data of a particular channel.

This is because, during this processing, the delay processing portion 14 must delay and output a quantity of SOH data.

BRIEF SUMMARY OF THE INVENTION

The object of the present invention is to supply a SDH test apparatus and a SDH test method that can solve

the problems mentioned above, and absorb the difference of AU data processing time by a simple configuration.

In order to achieve the aforementioned object, according to an aspect of the present invention, there is provided a SDH test apparatus for substituting a part of payload of received SDH data with a desired data and transmitting, comprising:

a Rx SOH processor for performing frame detection of the received SDH data;

a Rx AU processor for extracting AU data composed of AU pointer of data processed by the Rx SOH processor and payload, and detecting an information leading head position designated by the AU pointer;

a Tx AU processor for generating AU data wherein a part of payload of AU data extracted by the Rx AU processor is substituted with a desired data;

a Tx SOH processor for generating a new SDH data with AU data generated by the Tx AU processor and data from the Rx SOH processor and transmitting;

a FIFO memory installed between the Rx AU processor and the Tx AU processor, for storing sequentially payload of AU data extracted by the Rx AU processor and outputting to the Tx AU processor in the order of memorization; and

an AU pointer processor for outputting an AU pointer adjusting the number of data in the FIFO memory, allowing the Tx AU processor to read in payload

of AU data, after a time lag ($\Delta T_2 + \Delta T_4$) of information leading head position of payload generated by the processing of AU data by the Rx AU processor and the Tx AU processor, by extracting the number of data in the
5 FIFO memory,

wherein the Tx AU processor is composed to read out the payload of AU data from the FIFO memory, generate AU data and output to the Tx SOH processor so that the information leading position is at the
10 position designated by the AU pointer value output from the AU pointer processor.

In order to achieve the aforementioned object, according to another aspect of the present invention, there is provided a SDH test method for substituting
15 a part of payload of received SDH data with a desired data and transmitting, comprising the steps of:

Rx SOH processing including frame detection of the received SDH data;

Rx AU processing including extraction of AU data
20 composed of AU pointer of data processed by the Rx SOH processing and payload, and detection of the information leading head position designated by the AU pointer;

Tx AU processing including generation of AU data
25 wherein a part of payload of AU data extracted by the Rx AU processing is substituted with a desired data;

Tx SOH processing including generation of a new

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SDH data with AU data generated by the Tx AU processing and data by the Rx SOH processing and transmission thereof;

5 storing sequentially AU data extracted by the Rx AU processing between the Rx AU processing and the Tx AU processing in a FIFO memory and transmitting to the Tx AU processing in the order of memorization; and

10 AU pointer processing for outputting an AU pointer adjusting the number of data in the FIFO memory, allowing the Tx AU processing to read in payload of AU data, after a time lag ($\Delta T_2 + \Delta T_4$) of information leading head position of payload generated by the processing of AU data by the Rx AU processing and the Tx AU processing, by extracting the number of data in
15 the FIFO memory,

wherein the Tx AU processing is composed to read out the payload of AU data from the FIFO memory, generate AU data and output to the Tx AU processing so that the information leading position is at the
20 position designated by the AU pointer value output from the AU pointer processing.

Additional objects and advantages of the invention will be set forth in the description which follows, and in part will be obvious from the description, or may
25 be learned by practice of the invention. The objects and advantages of the invention may be realized and obtained by means of the instrumentalities and

combinations particularly pointed out hereinafter.

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWING

The accompanying drawings, which are incorporated in and constitute a part of the specification, illustrate presently preferred embodiments of the invention, and together with the general description given above and the detailed description of the preferred embodiments given below, serve to explain the principles of the invention.

FIG. 1 is a block diagram showing a configuration of one embodiment of the SDH test apparatus and SDH test method of the present invention;

FIGS. 2A to 2F are timing diagrams illustrating the operation of the SDH test apparatus of FIG. 1;

FIGS. 3A and 3B are data format diagrams illustrating the operation of the SDH test apparatus of FIG. 1;

FIG. 4 is a block diagram showing a configuration of a variant of the SDH test apparatus and SDH test method of the present invention;

FIG. 5 is a data format diagram of SDH format illustrating the prior art;

FIG. 6 is a diagram showing a SDH data transfer mode illustrating the prior art; and

FIG. 7 is a block diagram showing a configuration of an SDH test apparatus of the prior art.

DETAILED DESCRIPTION OF THE INVENTION

Reference will now be made in detail to the presently preferred embodiment of the invention as illustrated in the accompanying drawing, in which like reference numerals designate like or corresponding parts.

First, the outline of the present invention will be described.

The SDH test apparatus and SDH test method of the present invention are applied to the SDH test apparatus and SDH test method comprising a reception SOH processing portion (Rx SOH processor) 21 for performing a predetermined processing including frame detection of the received SDH data and error check of SOH portion; a reception AU processing portion (Rx AU processor) 22 for performing a predetermined processing including extraction of AU data composed of AU pointer of data processed by the Rx SOH processor and payload, and detection of the information leading head position designated by the AU pointer; a transmission AU processing portion (Tx AU processor) 25 for generating AU data wherein a part of payload of AU data extracted by the Rx AU processor is substituted with a desired data; a transmission SOH processing portion (Tx SOH processor) 26 for generating a new SDH data with AU data generated by the Tx AU processor and data from the Rx SOH processor and outputting, and transmitting by

substituting a part of data of payload of received SDH data with the desired data and transmitting.

And, the SDH test apparatus and SDH test method of the present invention comprise a FIFO memory (23) installed between the Rx AU processor and the Tx AU processor, for storing sequentially AU data extracted by the Rx AU processor and outputting to the Tx AU processor in the order of memorization, and an AU pointer processing portion (AU pointer processor) 24 for outputting an AU pointer adjusting the number of data in the FIFO memory, allowing the Tx AU processor to read in AU data payload (payload of AU data), after a time lag ($\Delta T2 + \Delta T4$) of information leading head position of payload generated by the processing of AU data by the Rx AU processor and the Tx AU processor, by extracting the number of data in the FIFO memory, wherein the Tx AU processor is composed to generate AU data and output to the Tx SOH processor so that the information leading position is at the position designated by the AU pointer value output from the AU pointer processor.

Now, the embodiment of the SDH test apparatus and SDH test method of the present invention based on the outline mentioned above will be described referring to the drawings.

FIG. 1 shows a configuration of a SDH test apparatus of one embodiment to which the SDH test

apparatus and SDH test method of the present invention are to be applied.

Namely, the SDH test apparatus of this embodiment is composed as follows.

5 A shown in FIG. 1, the Rx SOH processor 21 performs various processing including frame detection of input SDH data, channel selection, detection of data inserted in the SOH portion and error check or the like.

10 The Rx AU processor 22 performs various processing including extraction of AU portion of data processed by the Rx SOH processor 21, error check and detection of the information leading head position, and transmits the extracted AU data to the FIFO (first in first out)
15 memory 23.

The FIFO memory 23 stores AU data output from the Rx AU processor 22 in the order of output thereof, and outputs in the order of memorization.

20 The AU pointer processor 24 compensates the difference of the information leading position of payload generated by the processing time of AU portion by the Rx AU processor 22 and the Tx AU processor mentioned below, and the delay time to stationarily remain the number of data within the predetermined
25 range in the FIFO memory, by surveying the number of data remaining in the FIFO memory 23, deciding the AU pointer so that this number of data is kept within

a predetermined range, and outputting to the Tx AU processor 25.

The Tx AU processor 25 generates AU data so that the information leading position is at the position designated by the AU pointer value decided by the AU pointer processor 24, based on the data output from the FIFO memory 23 and a desired data (for instance, pseudo random data string) generated inside (may be input from the exterior), and outputs to the Tx SOH processor 26.

The Tx SOH processor 26 generates a SDH frame data, based on data from the Rx SOH processor 21 and AU data from the Tx AU processor and outputs.

Next, the operation of this SDH test apparatus shall be described.

As shown in FIG. 2A, if SSH data wherein SOH data of 8 bytes and payload of 261 bytes succeed alternatively is input, the Rx SOH processor 21 performs a predetermined processing such as frame synchronization processing of this SDH data, error check for SOH data or the like.

Then, this Rx SOH processor 21 outputs the processed SDH data, as shown in FIG. 2B, to the Rx AU processor 22 and the Tx SOH processor 26 delaying by the time $\Delta T1$ to the input data.

In FIGS. 2A to 2F, the reference symbol A indicates the information leading head position designated by the AU pointer AUP of the input SDH data.

The Rx AU processor 22 extracts AU portion (AU pointer AUP and payload) from this SDH data, performs a predetermined processing such as error check of this data or the like and, as shown in FIG. 2C, outputs data
5 delayed by the time $\Delta T2$ from the SDH data input from the Rx SOH processor 21.

There, the data from this Rx AU processor 22 is stored successively in the FIFO memory 23.

On the other hand, the AU pointer processor 24
10 allows to load AU data after the time lag of the information leading position of payload generated by the processing of AU data by the Rx AU processor 22 and the Tx AU processor 25 by deciding the AU pointer so that the number of data in the FIFO memory 23 enters
15 a predetermined range.

In other words, suppose the Tx SOH processor 26, as shown in FIG. 2F, outputs SOH portion and payload alternatively by a delay of $\Delta T3$ to the data (refer to FIG. 2B) from the Rx SOH processor, it is necessary
20 that the Tx AU processor, as shown in FIG. 2E, outputs AU data at a time point earlier by the processing time $\Delta T3$ of the Tx SOH processor 26, namely at the same timing as the data shown in FIG. 2B.

Suppose the processing time of the Tx AU processor
25 be $\Delta T4$, as shown in FIG. 2D, it is necessary that the FIFO memory 23 outputs AU data at a point earlier by $\Delta T4$ than the AU data output from the Tx AU

processor 25.

Consequently, suppose there is no delay by the FIFO memory 23, it is impossible to output the data of information leading head position A to the Tx SOH processor before $\Delta T2 + \Delta T4$ has elapsed from the time point when the data of information leading head position A of input SDH data is output from the Rx SOH processor 22.

However, after $\Delta T2 + \Delta T4$ has elapsed from the time point when the data of information leading head position A of input SDH data is output from the Rx SOH processor 22, the data of information leading head position A can be output to the Tx SOH processor 26.

And, this data can be placed at an arbitrary position in the payload output from the Tx SOH processor 26.

At this moment, the AU pointer is decided so that data of a predetermined range remains stationarily in the FIFO memory 23.

In other words, data remaining amount of FIFO memory 23 is monitored in frame synchronization, if it is less than the predetermined range, the AU pointer is increased by one and if it exceeds, the AU pointer is decreased by one.

The value A' of the AU pointer decided in this way, is inserted in the AUP in the frame and, at the same time, the position designated by this value A'

becomes the information leading head position.

On the other hand, suppose the delay time up to readout of data of the information leading head position A stored in this FIFO memory 23 be $\Delta T5$, as shown in FIG. 2E, data which was at this information leading head position A is output from the Tx AU processor 25, at the time point (namely A') when $\Delta T2 + \Delta T4 + \Delta T5$ has elapsed from the time point when the data of information leading head position A of input SDH data is output from the Rx SOH processor 22.

Thus, the Tx AU processor 25 generates a new AU data by inserting a desired data into a desired position taking the information leading head position A' as reference, and outputs with a delay of the time $\Delta T4$ as shown in FIG. 2E.

The AU data generated by this Tx AU processor 25 is input to the Tx SOH processor 26 with data from the Rx SOH processor 21 and thereby, as shown in FIG. 2F, a new SDH data is generated and output with a delay of the time $\Delta T3$.

By the processing mentioned above, as shown in FIG. 3A, the information leading head position of the SDH data having the information leading head position at the position A designated by the AU pointer AUP is shifted to the position A' designated by a newly decided AU pointer AUP, so as to include the processing time ($\Delta T2 + \Delta T4$) for AU data and a delay time $\Delta T5$

for maintaining the FIFO memory 23 data storage state stable, SDH data is converted into one wherein a desired data D is inserted to a predetermined position taking this information leading head position A' as
5 reference and output.

Thus, in the SDH test apparatus 20 of this embodiment, the difference of the information leading head position due to processing delay for AU data being compensated by AU pointer modification processing, the
10 delay processing of SDH data is unnecessary, increase of circuit scale is unnecessary, and SDH data wherein a part of data of payload of received SDH data is substituted with a desired data can be transmitted by a simple configuration.

15 In the foregoing, it has been described that only AU data is extracted from the received SDH data.

However, it may be composed as SDH test apparatus 20' shown in FIG. 4, if TU (tributary unit) data of deeper level in the payload.

20 In other words, the SDH test apparatus 20' shown in FIG. 4 is composed to extract TU data by a Rx TU processor 31 from data processed by the Rx AU processor 22, store this extracted TU data successively in the FIFO memory 32, output to the Tx TU processor 33 in
25 the order of this memorization, and at the same time, decide the TU pointer anticipating the information leading head position shifting due to the processing

time of TU data by the reception TU processing portion
31 (Rx TU processor) and the transmission TU processing
portion 33 (Tx TU processor), the delay time to
maintain the FIFO memory 32 data storage state stable,
5 by a TU pointer processing portion 34 (TU pointer
processor).

As mentioned above, the SDH test apparatus of the
present invention comprises a FIFO memory installed
between the Rx AU processor and the Tx AU processor,
10 for storing sequentially AU data extracted by the Rx
AU processor and outputting to the Tx AU processor in
the order of memorization, and an AU pointer processor
allowing to read in AU data, after a time lag of
information leading head position of payload generated
15 by the processing of AU data by the Rx AU processor and
the Tx AU processor, by deciding the AU pointer value
so that the number of data in the FIFO memory is in
a predetermined range, and the Tx AU processor is
composed to generate AU data and output to the Tx AU
20 processor so that the information leading position is
at the position designated by the AU pointer value
output from the AU pointer processor.

Consequently, according to the present invention,
a SDH test apparatus wherein the delay processing of
25 SDH data is unnecessary, increase of circuit scale
is unnecessary, and SDH data whose a part of data
of payload of received SDH data is substituted with

a desired data can be transmitted by a simple configuration, can be realized.

Additional advantages and modifications will readily occur to those skilled in the art. Therefore,
5 the invention in its broader aspects is not limited to the specific details and representative embodiments shown and described herein. Accordingly, various modifications may be made without departing from the spirit or scope of the general inventive concept as
10 defined by the appended claims and their equivalents.

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